

Notice of References Cited

 Application/Control No.
 10/849,256

 Applicant(s)/Patent Under
 Reexamination
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,151,285	11-2000	Watanabe et al.	720/610
*	B	US-6,195,225	02-2001	Komatsu et al.	360/99.01
*	C	US-6,275,460	08-2001	Nakayama et al.	720/610
*	D	US-6,208,605	03-2001	Akiba, Takao	720/613
*	E	US-6,313,965	11-2001	Yoneda, Haruhiko	360/84
*	F	US-6,320,835	11-2001	Kamei, Yo	720/653
*	G	US-6,341,115	01-2002	Otani et al.	720/653
*	H	US-6,529,461	03-2003	Watanabe et al.	720/732
*	I	US-7,093,268	08-2006	Kamei et al.	720/601
*	J	US-7,111,729	09-2006	Lau, Kwok Din	206/312
*	K	US-2003/0086358	05-2003	Park et al.	369/248
*	L	US-2003/0117928	06-2003	Choi et al.	369/75.2
*	M	US-2004/0205785	10-2004	Takahashi et al.	720/601

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08139471 A	05-1996	Japan	SAKAI, TOMOHIKO	
	O	JP 11025666 A	01-1999	Japan	AOYAMA et al.	
	P	JP 11186750 A	07-1999	Japan	TOMITA et al.	
	Q	JP 11345483 A	12-1999	Japan	EGUCHI et al.	
	R	JP 2000057742 A	02-2000	Japan	AEBA, KOJI	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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